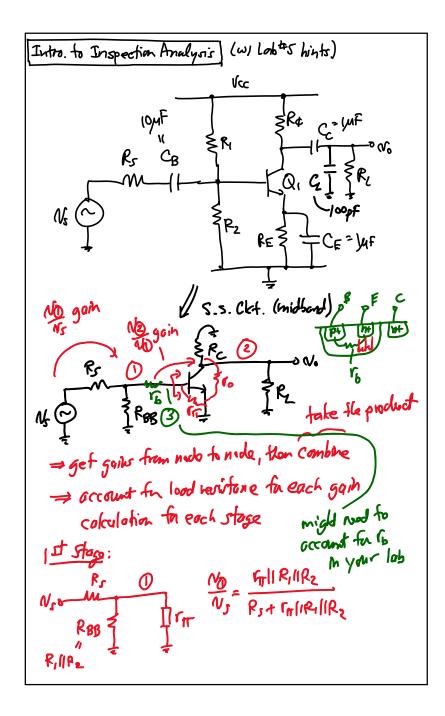
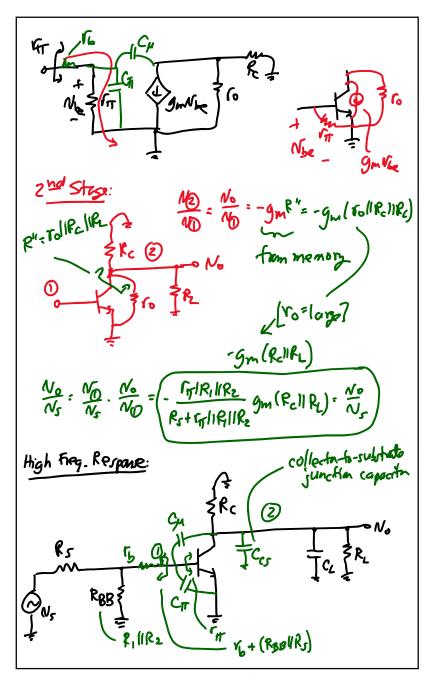
<u>EE 105</u>: Microelectronic Devices & Circuits <u>Lecture 27w</u>: Inspection Analysis & Miller Effect

Lecture 27: Inspection Analysis & Miller Effect Announcements: HW#9 online and due Friday via Gradescope Lab#5 due Tuesday, Nov. 12, 5 p.m. · Lecture Topics: ♥Intro. to Inspection Analysis & C.E. Design Project Hints Softer Amplifier Configurations & Generally-Loaded Transistor Last Time: • Started introduction to inspection analysis • Now continue with this ...



CTN 11/1/19



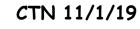


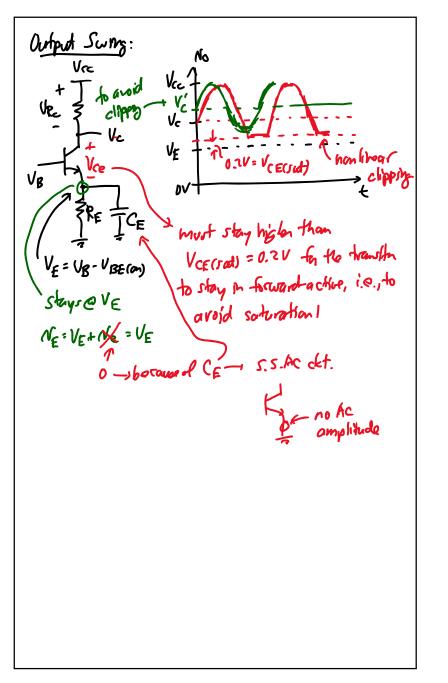
W4 · T0 + T0 + TFR all resistance ff node O to ground $\underline{\mathcal{G}}^{:} \quad \mathcal{I}_{\mathcal{O}}^{=} \quad C_{\pi} \left[\left(\mathbf{r}_{b} + \mathbf{R}_{SB} \mathbf{V} \mathbf{R}_{s} \right) \mathbf{V} \mathbf{r}_{\pi} \right] = C_{\pi} \mathbf{R}'$ $T_{O}: T_{O} = (C_{cs} + C_{c})(R_{L} || R_{c} || r_{o}) \approx (C_{cs} + C_{c})(R_{L} || R_{c})$ = (C_{cs}+C_c) R" all resistance fi node @ to ground $T_{B} \rightarrow T_{C_{\mu}}: T_{C_{\mu}} = (R' + R'' + g_{\mu}R'R'')C_{\mu}$ $\omega_{H}: \overline{C_{HR}' + (C_{es} + C_L)R'' + C_{\mu}(R' + R'' + G_{m}R'R'')}$ memorized often mast (marple) Important lab Hinto Noltugo dapacanos Re - rrr IIR, IIR, gm Rc ts+GrIIR, IIR, gm Rc If Re: IcRc: VRc ~ goin Va - to got a certain goin, need to ret Vc properly! Want more } = VRcT + VCBt - Cut + WHI $G_{\mu} = f(V_{CB}) - f(V_{CE})$ Fres. Rapane Constrainsgen!

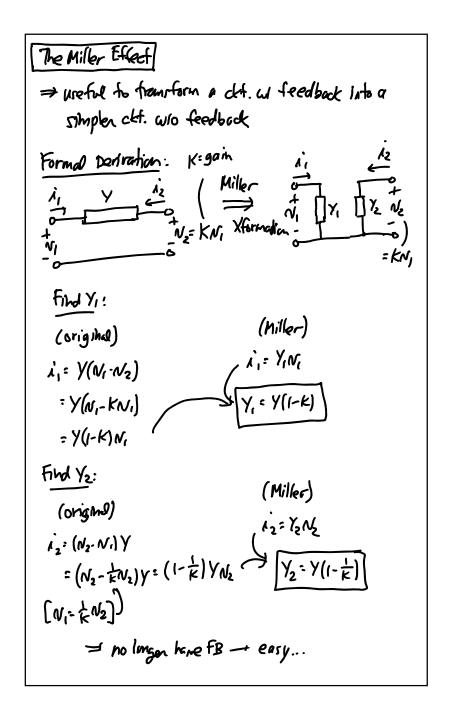
Copyright © 2019 Regents of the University of California

CTN 11/1/19

<u>EE 105</u>: Microelectronic Devices & Circuits <u>Lecture 27w</u>: Inspection Analysis & Miller Effect







<u>EE 105</u>: Microelectronic Devices & Circuits <u>Lecture 27w</u>: Inspection Analysis & Miller Effect

